



ED Japan

—by Akira Toriumi

Our annual IRPS 2013 Report Meeting was held at the University of Tokyo, Tokyo, July 25th. Dr. M. Sato, Toshiba gave a general review of IRPS 2013, which was held in April. Dr. K. Kobayashi, Kyoto Institute of Technology, reviewed the topics on circuit reliability and aging simulation and H. Matsuyama from Fujitsu Semiconductor, reviewed the topics on BEOL reliability. Following the topic reviews, eight selected papers from the conference were presented by their authors: C. Ma, Hiroshima University; Y. Yonamoto, Hitachi; A. Yonezawa, Tohoku University; S. Kudoh, Renesas Electronics; T. Uemura, Fujitsu Semiconductor; K. Miyachi, Chuo University; S. Fujii, Toshiba; and K. Joguchi, Chuo University. More than 60 attendees from the academic and corporate communities enjoyed the discussions on the latest device reliability issues.



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